Short Bio – Mr Marek Jemelka

Name: Marek Jemelka, M.Sc.

Marek Jemelka is Sales & Marketing Manager at NenoVision s.r.o., a Czech nanotechnology company developing LiteScope — an AFM-in-SEM instrument for correlative nanoscale analysis.

With a Master's in Materials Science & Engineering and prior experience with scientific instrumentation at CEITEC, Olympus IMS, and Evident Scientific, he bridges deep technical knowledge with commercial strategy.

At NenoVision, he drives global adoption of LiteScope across semiconductor FA, battery research, materials science, and life science labs.

NTU FACTS, NenoVision, Asia MatteLab, and Zeiss are pleased to present a workshop and live demonstration of the NenoVision LiteScope AFM integrated with the Zeiss Crossbeam 540 FIB-SEM.

The session will showcase correlative AFM, SEM, and EDX workflows for nanoscale surface characterization, topography imaging, and electrical and mechanical property mapping.

Participants are welcome to bring their own samples for evaluation (please indicate this in the registration form). Due to limited demonstration time, samples will be selected based on their suitability and compatibility with the demo setup.

Registration closes on 3 July 2026.

Topics covered:

1. AFM-in-FIB-SEM Technology
2. Correlative AFM, SEM & EDX Workflows
3. Surface Topography & Property Mapping
4. Advanced Semiconductor Failure Analysis
5. Battery Research & Manufacturing
6. Material Science & Engineering
7. Life Science & Pharma
8. Live Demonstration & Q&A